

## A 112 Gb/s -8.2 dBm Sensitivity 4-PAM Linear TIA in 16nm CMOS with Co-Packaged Photodiodes

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Low-cost optical receivers (RX) operating at 100+ Gb/s 4-PAM with low power are in high demand to support 400GBASE-DR4/FR4 links in data centers. Existing pluggable solutions generally realize the RX front-end in BiCMOS. However, a more integrated solution, with the RX front-ends integrated onto a CMOS host IC and co-packaged alongside the photodiodes (PDs), offers the potential for smaller size, lower cost, and lower power [1, 2]. This work demonstrates a 112 Gb/s 4-PAM linear TIA in CMOS flip-chip co-packaged with commercial PDs and different PD-to-RX interconnect lengths (Fig. 1a).

The interconnect between PD and RX runs along the package substrate, and its design impacts the front-end bandwidth (BW). When written in terms of its specific inductance and capacitance, we see that increasing the interconnect's characteristic impedance ( $Z_0 = \sqrt{L/C}$ ) makes it more inductive. This inductance appears between PD and RX capacitances and can perform series peaking. An optimized  $Z_0$  is obtained by selecting the appropriate interconnect width. We did so for two different PD-to-RX interconnect lengths, as shown in Fig. 1b. Optimal  $Z_0$  of 75  $\Omega$  and 50  $\Omega$  were achieved for 250  $\mu\text{m}$  and 500  $\mu\text{m}$  long interconnects, respectively resulting in similar BWs of approximately 60 GHz from the optical input to the PD to the TIA input in simulation (Fig. 1b).

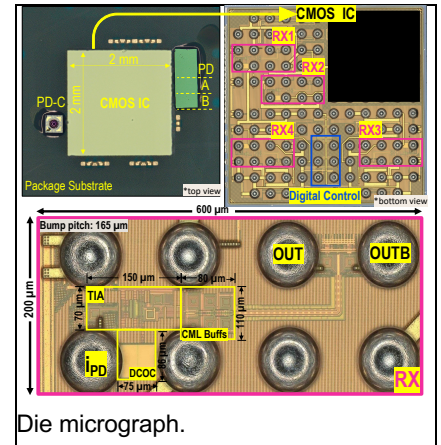
The proposed single-ended inverter-based TIA is shown in Fig. 2. A T-coil between the pad (100 fF) and TIA input with the center-tap connected to the ESD diode (80 fF) extends the BW. The TIA 1<sup>st</sup> stage is a shunt-feedback inverter providing 48 dB $\Omega$  of gain with 10 GHz of BW. Designing the 1<sup>st</sup> stage for a modest BW, 1/3 the overall TIA BW, allows for higher shunt resistor (Rf1) resulting in higher gain and lower input-referred current noise than a design with its full BW in the first TIA stage [3]. Subsequent equalizer stages restore the front-end to its targeted BW. The 1<sup>st</sup> stage is followed by a CTLE comprising an inverter-based transconductor for low-frequency gain in parallel with a CR high-pass filtered inverter. The high-pass filter cutoff frequency, and hence CTLE peaking, are adjusted by programmable resistors ( $R_{e1}$ ). The NMOS and PMOS transconductances are separately high-pass filtered to provide more programmability. A transimpedance stage (TIS) with shunt-feedback converts the CTLE transconductors' output current back to voltage. Overall, the 2<sup>nd</sup> stage provides a maximum of 4 dB boost around 25 GHz. The 3<sup>rd</sup> stage comprises a programmable inverter-based VGA in parallel with another CTLE similar to the one in the 2<sup>nd</sup> stage for further equalization. Finally, a large TIS with L1 in series and L2 in shunt-feedback provides further BW extension. The 3<sup>rd</sup> stage provides an additional 7 dB boost at 30 GHz.

The output node, DN, and the input node, DP, of the final TIS stage together form the TIA's pseudo-differential output. Deferring the single-ended to differential (S2D) conversion to the last stage allows for a lower power and lower noise single-ended TIA than a replica-based pseudo-differential TIA [4] or having S2D in the 1<sup>st</sup> stage [5]. Though not required in this work, a dedicated on-chip voltage regulator for the TIA can mitigate any additional supply noise [1, 2].

A 3-stage CML buffer with shunt-inductive peaking drives the TIA outputs for off-chip measurements while also reducing the common-mode content of the S2D pseudo-differential output signal. Overall, the CML buffers have 0 dB gain and 45 GHz 3dB-BW in simulations.

The RX prototype is fabricated in 16nm CMOS FinFET. Fig. 3 shows the electrical measurements of RX4 with TIA and CML buffers operating at 0.9V and 1.2V, respectively. They reveal a transimpedance gain of 63 dB $\Omega$ , BW of 32 GHz, dynamic range of 9 dB, and group delay variation of  $\leq \pm 5$  ps up to 32 GHz. Total harmonic distortion (THD) measurements show that up to 670  $\mu\text{A}_{\text{pp}}$  of input PD current can be handled with 8% of THD. 1-dB compression point with maximum gain occurs at 320  $\mu\text{A}_{\text{pp}}$ . Measured output voltage noise distribution reveals input-referred current noise density of 16.9 pA/ $\sqrt{\text{Hz}}$ .

As shown in the die micrograph figure, two commercial back-illuminated InP PD ICs were flip-attached onto the package substrate alongside the CMOS prototype TIAs. PD-C is a singlet with a responsivity of 0.7 A/W, whereas PD-A and PD-B are two from an array of four PDs with a responsivity of 0.6 A/W. The TIA (including ESD diode and T-coil) + DCOC blocks are seen to occupy 0.0165 mm<sup>2</sup> area.



A 112 Gb/s 4-PAM QPRBS13 pattern from an arbitrary waveform generator is amplified by a discrete driver and applied to a commercial Mach-Zehnder Modulator (MZM). A 1310nm laser source feeds the MZM through a single-mode fiber resulting in 4-PAM eyes with RLM >0.95 and outer ER >3 dB. Differential electrical outputs are observed through pads on top of the package.

Fig.4 (top) shows the individually measured 112 Gb/s 4-PAM differential output eye diagrams from RX[1:3] with -6.1 dBm OMA, each satisfying a minimum pre-FEC symbol error rate (SER) requirement of  $4.8 \times 10^{-4}$  without any on-scope equalization. Eye diagrams from RX1 and RX2, both having the same PD but with different package  $Z_0$  optimized for their respective PD-to-RX interconnect lengths, achieved similar eye quality. PD-C (in RX3) with 14% higher responsivity than PD-A/B achieved slightly better eye-opening compared to RX1/2. At its maximum gain setting, the TIA consumes 47 mW while the CML buffers consume 30 mW of power.

RX1 (w/ PD-A) eye diagrams after on-scope 4-tap FFE and 4-tap FFE + 4-tap DFE equalization are shown in Fig. 4 (bottom) further improving the eye quality. Fig. 5a shows the SER across input OMA indicating a sensitivity of -8.2 dBm at 112 Gb/s 4-PAM without scope equalization on RX1. Note that the SER does not reduce when the OMA is increased above -3 dBm limited by nonlinearity. Measurements with a 72 Gb/s NRZ PRBS13 input are shown in Fig. 5b achieving bit error rate (BER)  $< 1 \times 10^{-12}$  at -5.6 dBm without scope equalization. The BER further reduces to  $1 \times 10^{-16}$  with 4-tap FFE on-scope equalization as shown in Fig. 5b (bottom).

Fig. 6 shows a comparison with recent works in CMOS and a summary of the sensitivity measurements. Even with approximately 40% lower PD responsivity and higher PD+ESD capacitance, this work offers the highest data rate and best sensitivity at the same data rates compared with [1] and [2]. This work offers a data rate similar to [6], but with optical measurements (instead of only electrical) and with lower noise and power. Compared to [4], this work offers 56 Gb/s (5.7% higher) NRZ data rate with 5.7 dB better sensitivity at the cost of 26% higher power consumption. In summary, this proposed linear TIA co-packaged with commercial PDs and an optimized PD-to-RX interface demonstrates the potential for more integrated future 100+ Gb/s optical receivers.

### References:

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- [2] K. R. Lakshmikummar *et al.*, "A Process and Temperature Insensitive CMOS Linear TIA for 100 Gb/s/ $\lambda$  PAM-4 Optical Links," JSSC, Nov. 2019.
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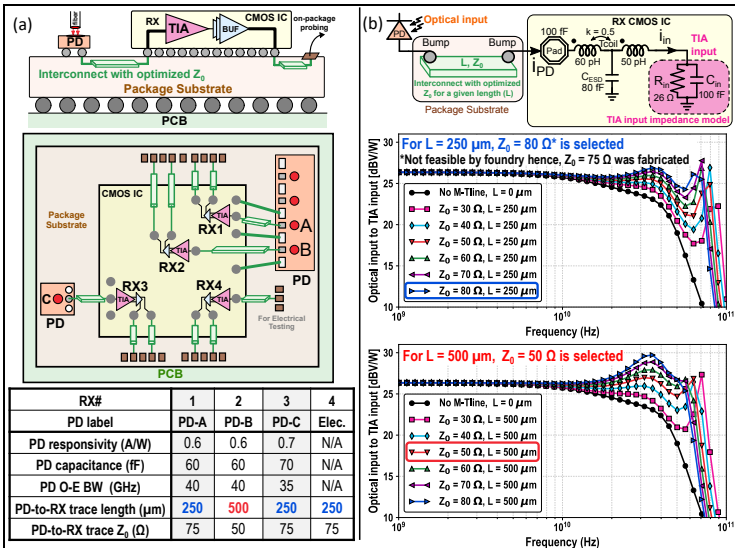


Fig. 1. (a) Co-packaged optical RX front-end architecture with four identical TIAs exercised with various PDs and PD-to-RX interconnect lengths (b) Passive front-end optimization.

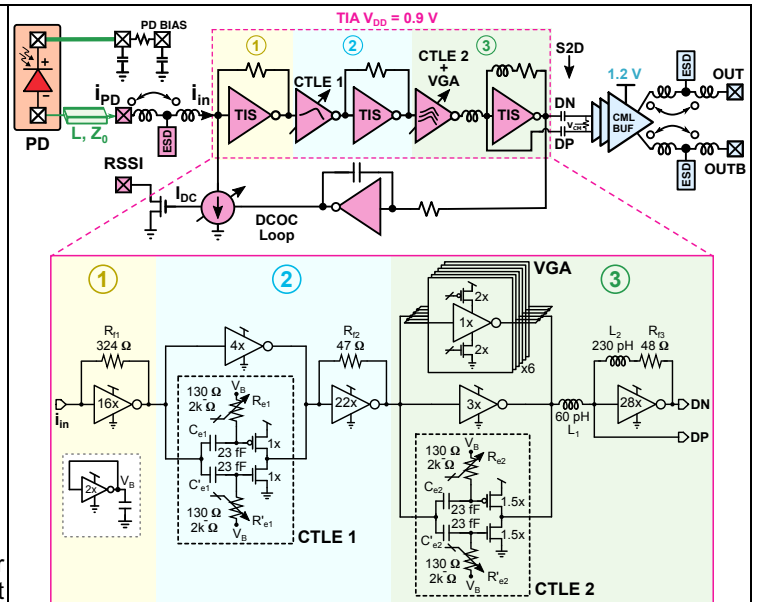


Fig. 2. Proposed Linear TIA schematic.

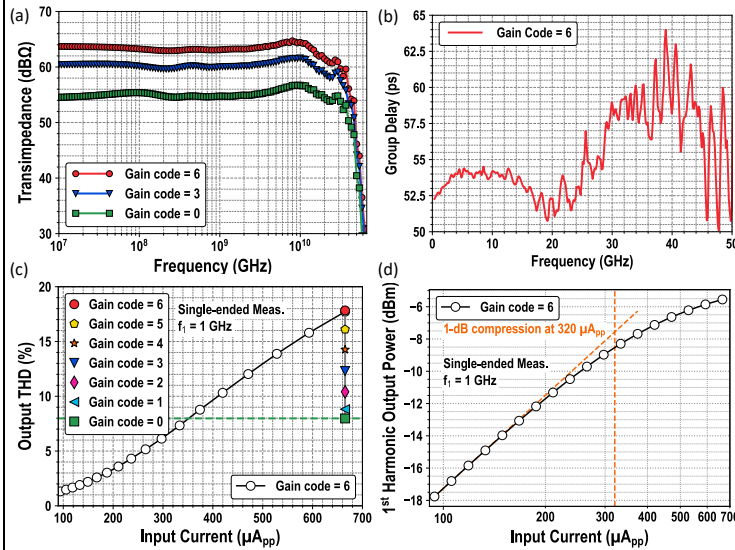


Fig. 3. Electrical measurements: (a) transimpedance, (b) group delay, (c) output THD and (d) 1-dB compression point.

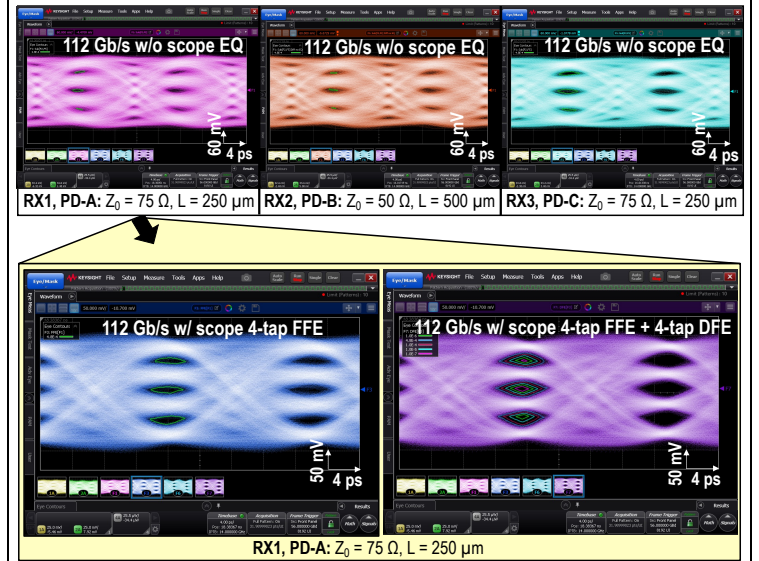


Fig. 4. 112 Gb/s 4-PAM RX differential output eye diagrams with -6.1 dBm input OMA.

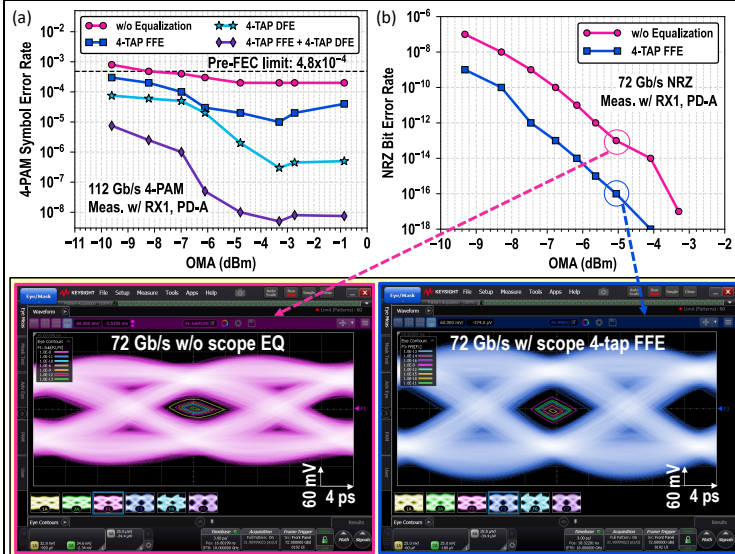


Fig. 5. (a) 112 Gb/s 4PAM SER (b) 72 Gb/s NRZ BER and differential output eye diagrams at -5.1 dBm OMA measured on RX1, PD-A.

	[4]	[6]	[2]	[1]	This Work
CMOS technology	28nm Bulk	28nm Bulk	16nm FinFET	28nm Bulk	16nm FinFET
Supply (V)	1.2	1.2, 2.5 (Vreg.)	1.8 (Vreg.)	1.5 (Vreg.)	0.9
Datarate (Gb/s)	53	112	106.25	100	112
Signaling	NRZ	4-PAM	4-PAM	4-PAM	4-PAM
TIA gain (dBΩ)	74	65	78	66*	63
TIA 3dB-BW (GHz)	27	60	27	20*	32
Max 4-PAM output swing w/ 50 Ω term. (mV <sub>p-p, sin</sub> )	N/A	300	300	620	450
Input ref. noise (pA/√Hz)	14*	19.3	16.7	21.2*	16.9
TIA power (mW)	34.6	107**	60.8**	117**	47
Input ESD (Yes/No)	No	No	No	No	Yes (80 fF)
PD capacitance (fF)	80		10	70	60
PD responsivity (A/W)	0.55		0.96	1	0.6
NRZ sensitivity at < 1x10 <sup>-12</sup> BER (dBm)	-6 dBm @53 Gb/s w/o scope eq.	N/A (Electrical measurements only)	N/A	N/A	-11.7 @56 Gb/s -5.6 @72 Gb/s w/ scope eq.
4-PAM sensitivity at < 4.8x10 <sup>-4</sup> SER (dBm)	N/A		-11 dBm @106.25 Gb/s w/ 5-tap FFE scope eq.	-8.3 dBm @100Gb/s w/ 2-tap FFE + 2-tap DFE on-chip eq.	-15 @100 Gb/s < -12.3 @106.25 Gb/s w/ 4-tap FFE + 4-tap DFE scope eq.

\*Simulated \*\*w/ output buffers and voltage regulators (approx. 20 ~ 40% of power consumed in voltage regulation)

4-PAM sensitivity summary at pre-FEC SER limit of 4.8x10 <sup>-4</sup> (dBm)					NRZ sensitivity summary at pre-FEC BER of 1x10 <sup>-12</sup> (dBm)		
Datarate (Gb/s)	w/o EQ	4-tap FFE	4-tap DFE	4-tap FFE + 4-tap DFE	Datarate (Gb/s)	w/o EQ	4-tap FFE
100	-12.5	-13.5	-14.5	-15	50	-13.9	< -15.1
106.25	-10.6		< -12.3		56	-11.7	-12.7
112	-8.2		< -9.6		64	-7.6	-10.4
					72	-5.6	-7.5

Fig. 6. Comparison to prior works and performance summary.